Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/799,429	PARIKH ET AL.
Examiner	**Art Unit**
Yicun Wu	2165

SEARCHED			
Class	Subclass	Date	Examiner
707	1-10, 100-104.1 200-206	12/19/2006	YW
704	9	12/19/2006	YW
715	744	12/19/2006	YW

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
inventor search (double patenting) uspto uspgpub epo jpo ibmtech derwent	12/19/2006	YW
acm ieee citeseer internet Search stratagy attached	12/19/2006	YW
consulted diane Mizrahi	12/19/2006	YW